

MCF Seminar Series

Scanning Electron Microscope (SEM)

Dr. Yordanos Bisrat

November 10, 2016

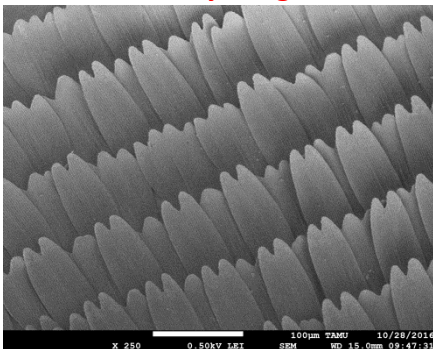
12:00 – 1:00PM

Giesecke Engineering Research Building (**ERB 154**)

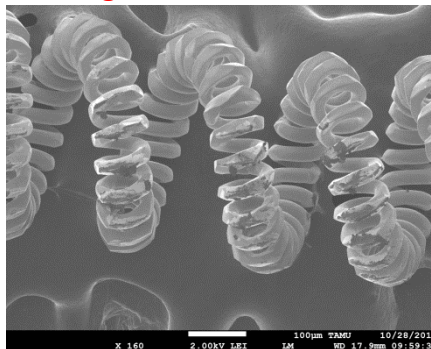
Directions to ERB: <http://aggiemap.tamu.edu/index.html?bldg=1611>

Description: The Scanning Electron Microscope (SEM) is an indispensable analytical tool whereby a focused electron beam interacts with atoms of a material at various depths within the material. As a result of these interactions, the SEM can provide information about a material's topography, morphology, phase distribution, compositional differences, and much more. This seminar will discuss the basic principles, application, and limitation of the SEM which would be beneficial to those researchers who are interested in the investigation of the processing, properties and behavior of materials that involve their microstructure.

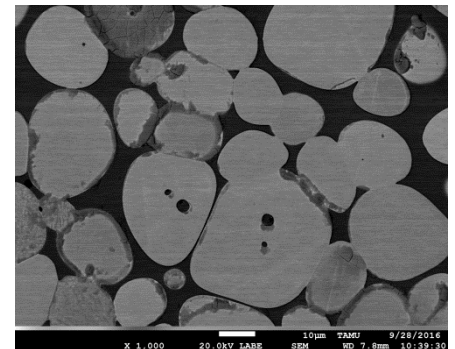
Butterfly wing



Light bulb filament



W particles in NiFeCo matrix



As seats are limited : [Register Here Now](#) 

***** Light refreshments will be provided *****
Free Parking is available